

Notice of References Cited	Application/Control No. 10/717,888	Applicant(s)/Patent Under Reexamination HAYNES ET AL.	
	Examiner Eric A. Wiener	Art Unit 2112	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-5,630,122	05-1997	Kaplan et al.	707/4
*	C	US-6,269,407	07-2001	Cink et al.	719/315
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*	E	US-5,956,508	09-1999	Johnson et al.	719/315
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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